## Marko Jak Tadjer

## List of Publications by Year in Descending Order

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The third column is the impact factor (IF) of the journal, and the fourth column is the number of citations of the article.

26 3,471 95 57 g-index h-index citations papers 4,385 96 5.85 3.3 L-index avg, IF ext. citations ext. papers

#	Paper	IF	Citations
95	A review of band structure and material properties of transparent conducting and semiconducting oxides: Ga2O3, Al2O3, In2O3, ZnO, SnO2, CdO, NiO, CuO, and Sc2O3. <i>Applied Physics Reviews</i> , <b>2022</b> , 9, 011315	17.3	27
94	Thermal effects in Ga2O3 rectifiers and MOSFETs borrowing from GaN <b>2022</b> , 441-467		
93	Reduced-stress nanocrystalline diamond films for heat spreading in electronic devices <b>2022</b> , 275-294		
92	A perspective on the electro-thermal co-design of ultra-wide bandgap lateral devices. <i>Applied Physics Letters</i> , <b>2021</b> , 119, 170501	3.4	8
91	Characterization of EGa2O3 homoepitaxial films and MOSFETs grown by MOCVD at high growth rates. <i>Journal Physics D: Applied Physics</i> , <b>2021</b> , 54, 034005	3	15
90	Two-step growth of EGa2O3 films on (100) diamond via low pressure chemical vapor deposition. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, <b>2021</b> , 39, 023411	2.9	6
89	Multi-frequency coherent emission from superstructure thermal emitters. <i>Applied Physics Letters</i> , <b>2021</b> , 118, 141102	3.4	2
88	Steady-state methods for measuring in-plane thermal conductivity of thin films for heat spreading applications. <i>Review of Scientific Instruments</i> , <b>2021</b> , 92, 044907	1.7	2
87	Vertical EGa2O3 Schottky rectifiers with 750 V reverse breakdown voltage at 600 K. <i>Journal Physics D: Applied Physics</i> , <b>2021</b> , 54, 305103	3	4
86	Influence of oxygen partial pressure on properties of monoclinic Ga2O3 deposited on sapphire substrates. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , <b>2021</b> , 39, 033414	2.9	
85	Delta-doped E(AlxGa1日)2O3/Ga2O3 heterostructure field-effect transistors by ozone molecular beam epitaxy. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , <b>2021</b> , 39, 03340	<del>2</del> .9	2
84	Engineering the Spectral and Spatial Dispersion of Thermal Emission via Polariton-Phonon Strong Coupling. <i>Nano Letters</i> , <b>2021</b> , 21, 1831-1838	11.5	16
83	Design of Ga2O3 modulation doped field effect transistors. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , <b>2021</b> , 39, 023412	2.9	4
82	Temperature dependent performance of ITO Schottky contacts on EGa2O3. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , <b>2021</b> , 39, 053405	2.9	6
81	Assessment of the (010) EGa2O3 surface and substrate specification. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , <b>2021</b> , 39, 013408	2.9	2
80	Effect of probe geometry during measurement of >100 A Ga2O3 vertical rectifiers. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , <b>2021</b> , 39, 013406	2.9	11
79	Collective Phonon-Polaritonic Modes in Silicon Carbide Subarrays ACS Nano, 2021,	16.7	4

78 Band Alignment of ScAlN/GaN Heterojunctions. ACS Applied Materials & amp; Interfaces, 2020, 12, 52192-522009 Band offset determination for amorphous Al2O3 deposited on bulk AlN and atomic-layer epitaxial 3.4 77 AlN on sapphire. Applied Physics Letters, 2020, 117, 182103 High-Resolution Thermoreflectance Imaging Investigation of Self-Heating in AlGaN/GaN HEMTs on 8 76 2.9 Si, SiC, and Diamond Substrates. IEEE Transactions on Electron Devices, 2020, 67, 5415-5420 Narrowband Polaritonic Thermal Emitters Driven by Waste Heat. ACS Omega, 2020, 5, 10900-10908 16 75 3.9 In Situ Transmission Electron Microscopy Observations of Forward Bias Degradation of Vertical 74 2 3 Geometry EGa2O3 Rectifiers. ECS Journal of Solid State Science and Technology, 2020, 9, 055008 Annealing Effects on the Band Alignment of ALD SiO2 on  $(InxGa1 \ \square)2O3$  for  $x = 0.25 \ \square.74$ . ECS 2 73 Journal of Solid State Science and Technology, 2020, 9, 045001 Asymmetrical Contact Geometry to Reduce Forward-Bias Degradation in EGa2O3 Rectifiers. ECS 72 2 5 Journal of Solid State Science and Technology, **2020**, 9, 035007 Changes in band alignment during annealing at 600 LC of ALD Al2O3 on (InxGa1 Lk)2O3 for 2.5 x = 0.250.74. *Journal of Applied Physics*, **2020**, 127, 105701 In Situ Observation of EGa2O3 Schottky Diode Failure Under Forward Biasing Condition. IEEE 70 2.9 7 Transactions on Electron Devices, 2020, 67, 3056-3061 Integration of polycrystalline Ga2O3 on diamond for thermal management. Applied Physics Letters, 69 42 3.4 2020, 116, 062105 68 Phonon Properties. Springer Series in Materials Science, 2020, 501-534 0.9 1 Design and implementation of floating field ring edge termination on vertical geometry EGa2O3 67 2.9 rectifiers. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2020, 38, 063414 Long-wavelength dielectric properties and infrared active optical phonon modes of molecular 66 beam epitaxy ScxAl1\( \overline{A} \) N determined by infrared spectroscopic ellipsometry. Applied Physics Letters 6 3.4 , **2020**, 117, 232107 Structural and electronic properties of Si- and Sn-doped (201) EGa2O3 annealed in nitrogen and 65 10 oxygen atmospheres. Journal Physics D: Applied Physics, 2020, 53, 504002 Structural transition and recovery of Ge implanted EGa2O3. Applied Physics Letters, 2020, 117, 152101 64 18 Forward bias degradation and thermal simulations of vertical geometry EGa2O3 Schottky 63 rectifiers. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2019, 1.3 11 37, 061205 Band Offsets of Insulating & Semiconducting Oxides on (AlxGa1-x)O3. ECS Transactions, 2019, 92, 79-88 1 62 5 High Performance \${beta}\$ -Ga2O3 Nano-Membrane Field Effect Transistors on a High Thermal 61 2.3 24 Conductivity Diamond Substrate. IEEE Journal of the Electron Devices Society, 2019, 7, 914-918

60	Diffusion of implanted Ge and Sn in EGa2O3. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , <b>2019</b> , 37, 051204	1.3	16
59	Effect of thermal annealing for W/EGa2O3 Schottky diodes up to 600 LC. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , <b>2019</b> , 37, 061201	1.3	10
58	Switching Behavior and Forward Bias Degradation of 700V, 0.2A, EGa2O3Vertical Geometry Rectifiers. <i>ECS Journal of Solid State Science and Technology</i> , <b>2019</b> , 8, Q3028-Q3033	2	12
57	Implementation of a 900IV Switching Circuit for High Breakdown Voltage EGa2O3 Schottky Diodes. <i>ECS Journal of Solid State Science and Technology</i> , <b>2019</b> , 8, Q3229-Q3234	2	7
56	Vertical geometry 33.2 A, 4.8 MW cm2 Ga2O3 field-plated Schottky rectifier arrays. <i>Applied Physics Letters</i> , <b>2019</b> , 114, 232106	3.4	26
55	Thermoreflectance Temperature Mapping of Ga2O3 Schottky Barrier Diodes. <i>ECS Transactions</i> , <b>2019</b> , 89, 3-7	1	3
54	GaN-On-Diamond HEMT Technology With TAVG = 176°C at PDC,max = 56 W/mm Measured by Transient Thermoreflectance Imaging. <i>IEEE Electron Device Letters</i> , <b>2019</b> , 40, 881-884	4.4	28
53	Tunable Thermal Energy Transport across Diamond Membranes and Diamond-Si Interfaces by Nanoscale Graphoepitaxy. <i>ACS Applied Materials &amp; Samp; Interfaces</i> , <b>2019</b> , 11, 18517-18527	9.5	30
52	Damage Recovery and Dopant Diffusion in Si and Sn Ion Implanted EGa2O3. <i>ECS Journal of Solid State Science and Technology</i> , <b>2019</b> , 8, Q3133-Q3139	2	20
51	Reverse Breakdown in Large Area, Field-Plated, Vertical EGa2O3Rectifiers. <i>ECS Journal of Solid State Science and Technology</i> , <b>2019</b> , 8, Q3159-Q3164	2	16
50	Longitudinal phonon plasmon mode coupling in EGa2O3. Applied Physics Letters, 2019, 114, 102102	3.4	16
49	Valence and Conduction Band Offsets for InN and III-Nitride Ternary Alloys on (201) Bulk EGa2O3. <i>ECS Journal of Solid State Science and Technology</i> , <b>2019</b> , 8, Q3154-Q3158	2	9
48	Thermal conductance across EGa2O3-diamond van der Waals heterogeneous interfaces. <i>APL Materials</i> , <b>2019</b> , 7, 031118	5.7	63
47	Editors' Choice <b>R</b> eviewTheory and Characterization of Doping and Defects in EGa2O3. <i>ECS Journal of Solid State Science and Technology</i> , <b>2019</b> , 8, Q3187-Q3194	2	89
46	Vertical Ga2O3 Schottky Barrier Diodes With Small-Angle Beveled Field Plates: A Baliga Figure-of-Merit of 0.6 GW/cm2. <i>IEEE Electron Device Letters</i> , <b>2019</b> , 40, 1399-1402	4.4	84
45	The role of annealing ambient on diffusion of implanted Si in EGa2O3. AIP Advances, <b>2019</b> , 9, 085111	1.5	18
44	Band Alignment of Atomic Layer Deposited SiO2 and Al2O3 on (AlxGa1-x)2O3 for $x = 0.2$ -0.65. ECS Journal of Solid State Science and Technology, <b>2019</b> , 8, P351-P356	2	8
43	Demonstration of Cul as a PN heterojunction toEGa2O3. <i>Applied Physics Express</i> , <b>2019</b> , 12, 104005	2.4	4

## (2018-2019)

42	Defect Characterization of Multicycle Rapid Thermal Annealing Processed p-GaN for Vertical Power Devices. <i>ECS Journal of Solid State Science and Technology</i> , <b>2019</b> , 8, P70-P76	2	6
41	Effect of Annealing on the Band Alignment of ALD SiO2 on (AlxGa1-x)2O3 for $x = 0.2 - 0.65$ . ECS Journal of Solid State Science and Technology, <b>2019</b> , 8, P751-P756	2	4
40	Lateral GaN JFET Devices on Large Area Engineered Substrates. <i>ECS Journal of Solid State Science and Technology</i> , <b>2019</b> , 8, Q226-Q229	2	2
39	Dynamic Switching Characteristics of 1 A Forward Current \$boldsymbol{beta}\$ -Ga2O3 Rectifiers. <i>IEEE Journal of the Electron Devices Society</i> , <b>2019</b> , 7, 57-61	2.3	20
38	Ohmic contacts to gallium oxide <b>2019</b> , 211-230		4
37	Electrical characterization of ALD HfO2 high-k dielectrics on ( 201) EGa2O3. <i>Applied Physics Letters</i> , <b>2018</b> , 112, 042107	3.4	38
36	A review of Ga2O3 materials, processing, and devices. <i>Applied Physics Reviews</i> , <b>2018</b> , 5, 011301	17.3	1114
35	(Invited) Fabrication and Characterization of EGa2O3Heterojunction Rectifiers. <i>ECS Transactions</i> , <b>2018</b> , 85, 21-26	1	9
34	Electrothermal Evaluation of AlGaN/GaN Membrane High Electron Mobility Transistors by Transient Thermoreflectance. <i>IEEE Journal of the Electron Devices Society</i> , <b>2018</b> , 6, 922-930	2.3	7
33	Heterostructure WSe-GaO Junction Field-Effect Transistor for Low-Dimensional High-Power Electronics. <i>ACS Applied Materials &amp; </i>	9.5	60
32	Ga2O3 Schottky rectifiers with 1 ampere forward current, 650 V reverse breakdown and 26.5 MW.cm-2 figure-of-merit. <i>AIP Advances</i> , <b>2018</b> , 8, 055026	1.5	51
31	Ga2O3 Schottky barrier and heterojunction diodes for power electronics applications 2018,		17
30	Full 3D Thermal Simulation of GaN HEMT using Ultra-Fast Self-Adaptive Computations Driven by Experimentally Determined Thermal Maps <b>2018</b> ,		2
29	High resistivity halide vapor phase homoepitaxial EGa2O3 films co-doped by silicon and nitrogen. <i>Applied Physics Letters</i> , <b>2018</b> , 113, 192102	3.4	27
28	Cheap Ultra-Wide Bandgap Power Electronics? Gallium Oxide May Hold the Answer. <i>Electrochemical Society Interface</i> , <b>2018</b> , 27, 49-52	3.6	18
27	Perspective: Ga2O3 for ultra-high power rectifiers and MOSFETS. <i>Journal of Applied Physics</i> , <b>2018</b> , 124, 220901	2.5	245
26	Lateral GaN JFET Devices on 200 mm Engineered Substrates for Power Switching Applications <b>2018</b> ,		3
25	Effect of surface treatments on electrical properties of EGa2O3. <i>Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics</i> , <b>2018</b> , 36, 061201	1.3	30

24	Valence band offsets for CuI on (-201) bulk Ga2O3 and epitaxial (010) (Al0.14Ga0.86)2O3. <i>Applied Physics Letters</i> , <b>2018</b> , 113, 182101	3.4	12
23	2300V Reverse Breakdown Voltage Ga2O3Schottky Rectifiers. <i>ECS Journal of Solid State Science and Technology</i> , <b>2018</b> , 7, Q92-Q96	2	116
22	A Tri-Layer PECVD SiN Passivation Process for Improved AlGaN/GaN HEMT Performance. <i>ECS Journal of Solid State Science and Technology</i> , <b>2017</b> , 6, P58-P61	2	9
21	Thermionic Emission Analysis of TiN and Pt Schottky Contacts to EGa2O3. <i>ECS Journal of Solid State Science and Technology</i> , <b>2017</b> , 6, P165-P168	2	31
20	Hexagonal boron nitride particles for determining the thermal conductivity of diamond films based on near-ultraviolet micro-Raman mapping. <i>Journal Physics D: Applied Physics</i> , <b>2017</b> , 50, 24LT01	3	3
19	Quasi-Two-Dimensional h-BN/EGaO Heterostructure Metal-Insulator-Semiconductor Field-Effect Transistor. <i>ACS Applied Materials &amp; Discrete Semiconductor Field-Effect Semiconductor Field-Effect Semiconductor Field-Effect Pransistor. ACS Applied Materials &amp; Discrete Field-Effect Pransistor. ACS Applied Pransistor. ACS Appl</i>	9.5	71
18	Vertical GaN Junction Barrier Schottky Diodes. <i>ECS Journal of Solid State Science and Technology</i> , <b>2017</b> , 6, Q10-Q12	2	18
17	Band Alignments of Atomic Layer Deposited ZrO2and HfO2High-k Dielectrics with (-201) EGa2O3. <i>ECS Journal of Solid State Science and Technology</i> , <b>2017</b> , 6, Q3052-Q3055	2	57
16	Quantifying substrate removal induced electrothermal degradation in AlGaN/GaN HEMTs 2017,		3
15	Electrothermal evaluation of thick GaN epitaxial layers and AlGaN/GaN high-electron-mobility transistors on large-area engineered substrates. <i>Applied Physics Express</i> , <b>2017</b> , 10, 126501	2.4	10
14	Optical characterization and thermal properties of CVD diamond films for integration with power electronics. <i>Solid-State Electronics</i> , <b>2017</b> , 136, 12-17	1.7	13
13	Temperature and electric field induced metal-insulator transition in atomic layer deposited VO2 thin films. <i>Solid-State Electronics</i> , <b>2017</b> , 136, 30-35	1.7	13
12	Vertical GaN Junction Barrier Schottky Rectifiers by Selective Ion Implantation. <i>IEEE Electron Device Letters</i> , <b>2017</b> , 38, 1097-1100	4.4	96
11	Nanocrystalline diamond capped AlGaN/GaN high electron mobility transistors via a sacrificial gate process. <i>Physica Status Solidi (A) Applications and Materials Science</i> , <b>2016</b> , 213, 893-897	1.6	17
10	Selective p-type Doping of GaN:Si by Mg Ion Implantation and Multicycle Rapid Thermal Annealing. <i>ECS Journal of Solid State Science and Technology</i> , <b>2016</b> , 5, P124-P127	2	32
9	Structural, Optical, and Electrical Characterization of Monoclinic EGa2O3 Grown by MOVPE on Sapphire Substrates. <i>Journal of Electronic Materials</i> , <b>2016</b> , 45, 2031-2037	1.9	92
8	Homoepitaxial growth of EGa2O3 thin films by low pressure chemical vapor deposition. <i>Applied Physics Letters</i> , <b>2016</b> , 108, 182105	3.4	145
7	Heteroepitaxy of N-type EGa2O3 thin films on sapphire substrate by low pressure chemical vapor deposition. <i>Applied Physics Letters</i> , <b>2016</b> , 109, 132103	3.4	96

## LIST OF PUBLICATIONS

6	Editors' Choice Communication (001) EGa2O3MOSFET with +2.9 V Threshold Voltage and HfO2Gate Dielectric. <i>ECS Journal of Solid State Science and Technology</i> , <b>2016</b> , 5, P468-P470	2	106
5	Atomic Layer Epitaxy AlN for Enhanced AlGaN/GaN HEMT Passivation. <i>IEEE Electron Device Letters</i> , <b>2013</b> , 34, 1115-1117	4.4	39
4	Degradation of dynamic ON-resistance of AlGaN/GaN HEMTs under proton irradiation 2013,		12
3	. IEEE Electron Device Letters, <b>2012</b> , 33, 23-25	4.4	83
	Simultaneous Evaluation of Heat Capacity and In-plane Thermal Conductivity of Nanocrystalline		
2	Diamond Thin Films. Nanoscale and Microscale Thermophysical Engineering,1-13	3.7	1